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Docket No.: NIP-002

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Confirmation No.

Toshihisa WATANAE et al.

U.S. Patent Application No.: -----

Group Art Unit: -----

Filed: herewith

For: X-RAY DETECTION DEVICE FOR FOREIGN MATTER

PRELIMINARY AMENDMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

Preliminary to examination of the above-referenced application, please amend the application as follows:

AMENDMENTS TO THE CLAIMS

REMARKS